

<b>Notice of References Cited</b>	Application/Control No. 10/826,799		Applicant(s)/Patent Under Reexamination DEPUE ET AL.	
	Examiner David L. Lewis		Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0231482	10-2005	Theytaz et al.	345/166
*	B	US-7,161,582	01-2007	Bathiche et al.	345/156
*	C	US-2005/0190157	09-2005	Oliver et al.	345/166
*	D	US-2005/0035947	02-2005	Lutian, John Michael	345/166
*	E	US-7,116,427	10-2006	Baney et al.	345/166
*	F	US-2005/0073693	04-2005	DePue et al.	356/499
*	G	US-6,657,184	12-2003	Anderson et al.	345/166
*	H	US-6,934,037	08-2005	DePue et al.	356/498
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	X	

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